

Search Notes

Application No.

10/601,147

Examiner

Erin D Chiem

Applicant(s)

GUNN ET AL.

Art Unit

2883

SEARCHED

Class	Subclass	Date	Examiner
385	37	2/2/2005	EDC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PLUS search	2/3/2005	EDC
INVENTOR search	2/2/2005	EDC
array\$4 near3 grating near3 coupl\$6 and transistor and wafer near4 bond\$	2/3/2005	EDC
active near alignment and optic\$6 near device same array	2/3/2005	EDC
ALIGN\$6 NEAR3 optic\$4 near3 device same method and automat\$6 near5 align\$6 and align\$6 same pattern near5 recogni\$8	2/2/2005	EDC